


<b>Search Notes</b>  	<b>Application/Control No.</b>  10815350	<b>Applicant(s)/Patent Under Reexamination</b>  HATHERILL ET AL.
	<b>Examiner</b>  Han, Jason M	<b>Art Unit</b>  2875

SEARCHED			
Class	Subclass	Date	Examiner
362	167, 197-199, 232, 250, 418-419, 427-428, 800	7/5/2006	JMH
362	396, 398	2/5/2007	JMH

SEARCH NOTES		
Search Notes	Date	Examiner
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	7/5/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	2/5/2007	JMH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	EAST (US-PGPUB) - See Printout	2/5/2007	JMH